L Number	Hits	Search Text	DB	Time stamp
1	4572	(electron adj beam) and (electron adj source)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 15:44
2	1149	((electron adj beam) and (electron adj source)) and sample	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 15:44
3	284	(((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 15:45
4	201	((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 15:45
5	196	(((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage) and scanning	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 15:47
6	182	((((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage) and scanning) and (secondary adj electron)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 15:46
7	36	(((((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage) and scanning) and (secondary adj electron)) and backscatter$3	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 15:47
8	8	((((((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage) and scanning) and (secondary adj electron)) and backscatter$3) and (scanning near4 speed)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 16:11
9	12	((((((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage) and scanning) and (secondary adj electron)) and backscatter$3) and ((two or several or multi) near4 scan$4)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 16:22
10	0	(((((((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage) and scanning) and (secondary adj electron)) and backscatter$3) and ((two or several or multi) near4 scan$4)) and (two near4 spead)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 16:23
11	11	(((((((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage) and scanning) and (secondary adj electron)) and backscatter$3) and ((two or several or multi) near4 scan$4)) and (two near4 scan$4)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 16:23
12	6	((((((((((electron adj beam) and (electron adj source)) and sample) and (electron adj detector)) and stage) and scanning) and (secondary adj electron)) and backscatter$3) and ((two or several or multi) near4 scan$4)) and (two near4 scan$4)) and (scan$4 near4 deflection)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/06/09 16:25